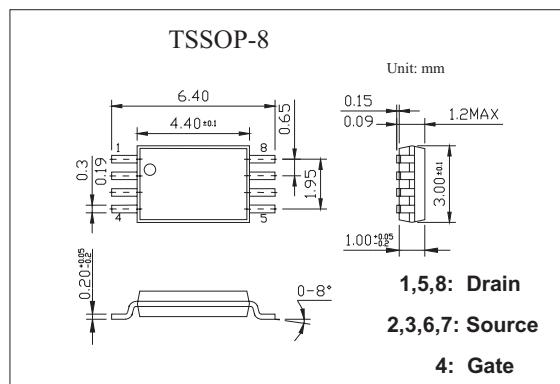
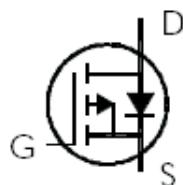


## HEXFET® Power MOSFET

### KRF7703

#### ■ Features

- Ultra Low On-Resistance
- P-Channel MOSFET
- Very Small SOIC Package
- Low Profile (< 1.2mm)
- Available in Tape & Reel



#### ■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Drain- Source Voltage	V <sub>DS</sub>	-40	V
Continuous Drain Current, V <sub>GS</sub> @ -10V @ Ta = 25°C	I <sub>D</sub>	-6.0	A
Continuous Drain Current, V <sub>GS</sub> @ -10V @ Ta = 70°C	I <sub>D</sub>	-4.7	
Pulsed Drain Current *1	I <sub>DM</sub>	-24	
Power Dissipation *2 @Ta= 25°C	P <sub>D</sub>	1.5	W
Power Dissipation *2 @Ta = 70°C	P <sub>D</sub>	0.96	W
Linear Derating Factor		0.012	W/°C
Gate-to-Source Voltage	V <sub>GS</sub>	±20	V
Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to + 150	°C
Maximum Junction-to-Ambient *2	R <sub>θ JA</sub>	83	°C/W

\*1 Repetitive rating; pulse width limited by max. junction temperature.

\*2 Surface mounted on 1 in square Cu board

**KRF7703**■ Electrical Characteristics  $T_a = 25^\circ\text{C}$ 

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250 \mu\text{A}$	-40			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	$I_D = -1\text{mA}$ , Reference to $25^\circ\text{C}$		0.030		$\text{V}/^\circ\text{C}$
Static Drain-to-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_D = -6.0\text{A}^*\text{1}$			28	$\text{m}\Omega$
		$V_{\text{GS}} = -4.5\text{V}, I_D = -4.8\text{A}^*\text{1}$			45	
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250 \mu\text{A}$	-1.0		-3.0	V
Forward Transconductance	$g_{\text{fs}}$	$V_{\text{DS}} = -10\text{V}, I_D = -6.0\text{A}^*\text{1}$	10			S
Drain-to-Source Leakage Current	$I_{\text{DSS}}$	$V_{\text{DS}} = -32\text{V}, V_{\text{GS}} = 0\text{V}$			-15	$\mu\text{A}$
		$V_{\text{DS}} = -32\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 70^\circ\text{C}$			-25	
Gate-to-Source Forward Leakage	$I_{\text{GSS}}$	$V_{\text{GS}} = -20\text{V}$			-100	nA
Gate-to-Source Reverse Leakage		$V_{\text{GS}} = 20\text{V}$			100	
Total Gate Charge	$Q_g$	$I_D = -6.0\text{A}$		41	62	nC
Gate-to-Source Charge	$Q_{\text{gs}}$	$V_{\text{DS}} = -20\text{V}$		16	25	
Gate-to-Drain ("Miller") Charge	$Q_{\text{gd}}$	$V_{\text{GS}} = -10\text{V}$		16	24	
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -20\text{V}, V_{\text{GS}} = -10\text{V}$		43		ns
Rise Time	$t_r$	$I_D = -1.0\text{A}$		405		
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$	$R_G = 6 \Omega$		155		
Fall Time	$t_f$			77		
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}$		5220		pF
Output Capacitance	$C_{\text{oss}}$	$V_{\text{DS}} = -25\text{V}$		416		
Reverse Transfer Capacitance	$C_{\text{rss}}$	$f = 1.0\text{MHz}$		337		
Continuous Source Current (Body Diode)	$I_s$	MOSFET symbol showing the integral reverse p-n junction diode.			-1.5	A
Pulsed Source Current (Body Diode) *2	$I_{\text{SM}}$				-24	
Diode Forward Voltage	$V_{\text{sd}}$	$T_J = 25^\circ\text{C}, I_s = -1.5\text{A}, V_{\text{GS}} = 0\text{V}^*\text{1}$			-1.2	V
Reverse Recovery Time	$t_{\text{rr}}$	$T_J = 25^\circ\text{C}, I_F = -1.5\text{A}$		34	51	ns
Reverse RecoveryCharge	$Q_{\text{rr}}$	$dI/dt = -100\text{A}/\mu\text{s}^*\text{1}$		56	84	$\mu\text{C}$

\*1 Pulse width  $\leq 400 \mu\text{s}$ ; duty cycle  $\leq 2\%$ .

\*2 Repetitive rating; pulse width limited by max. junction temperature.